

TOSHIBA Field Effect Transistor Silicon N Channel Junction Type

2SK881

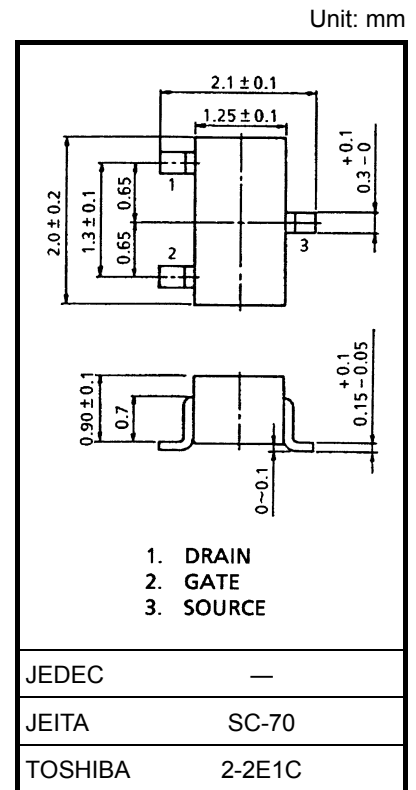
FM Tuner Applications
VHF Band Amplifier Applications

- Low noise figure: $NF = 2.5\text{dB (typ.)}$ ($f = 100\text{ MHz}$)
- High forward transfer admittance: $|Y_{fs}| = 9\text{ mS (typ.)}$

Absolute Maximum Ratings ($T_a = 25^\circ\text{C}$)

Characteristics	Symbol	Rating	Unit
Gate-drain voltage	V_{GDO}	-18	V
Gate current	I_G	10	mA
Drain power dissipation	P_D	100	mW
Junction temperature	T_j	125	$^\circ\text{C}$
Storage temperature range	T_{stg}	-55~125	$^\circ\text{C}$

Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings.
Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

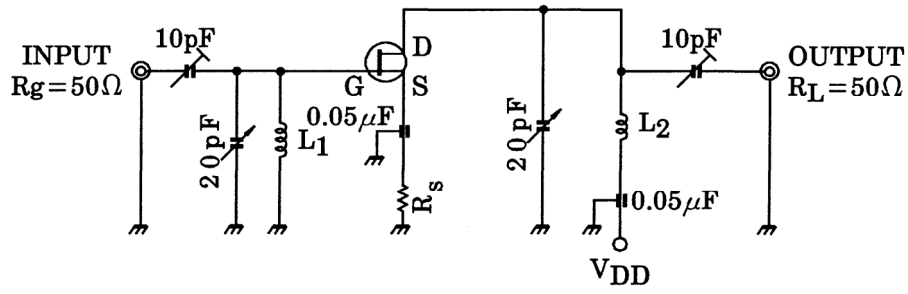


Weight: 0.006 g (typ.)

Electrical Characteristics ($T_a = 25^\circ\text{C}$)

Characteristics	Symbol	Test Condition	Min	Typ.	Max	Unit
Gate leakage current	I_{GSS}	$V_{GS} = -0.5\text{ V}, V_{DS} = 0$	—	—	-10	nA
Gate-drain breakdown voltage	$V_{(BR)GDO}$	$I_G = -10\ \mu\text{A}$	-18	—	—	V
Drain current	I_{DSS} (Note)	$V_{GS} = 0, V_{DS} = 10\text{ V}$	1.0	—	10	mA
Gate-source cut-off voltage	$V_{GS(OFF)}$	$V_{DS} = 10\text{ V}, I_D = 1\ \mu\text{A}$	-0.4	—	-4.0	V
Forward transfer admittance	$ Y_{fs} $	$V_{GS} = 0, V_{DS} = 10\text{ V}, f = 1\text{ kHz}$	—	9	—	mS
Input capacitance	C_{iss}	$V_{DS} = 10\text{ V}, V_{GS} = 0, f = 1\text{ MHz}$	—	6.0	—	pF
Reverse transfer capacitance	C_{rss}	$V_{DS} = 10\text{ V}, V_{GS} = 0, f = 1\text{ MHz}$	—	—	0.15	pF
Power gain	G_{ps}	$V_{DD} = 10\text{ V}, f = 100\text{ MHz}$ (Figure 1)	10	18	—	dB
Noise figure	NF	$V_{DD} = 10\text{ V}, f = 100\text{ MHz}$ (Figure 1)	—	2.5	3.5	dB

Note: I_{DSS} classification O: 1.0~3.0, Y: 2.5~6.0, GR: 5.0~10.0



L1: 0.8 mmφ Ag plated Cu wire, 3 turns, 10 mm ID, 10 mm length.

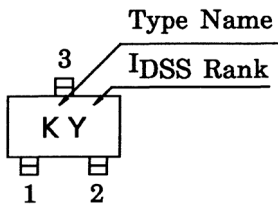
L2: 0.8 mmφ Ag plated Cu wire, 3.5 turns, 10 mm ID, 10 mm length.

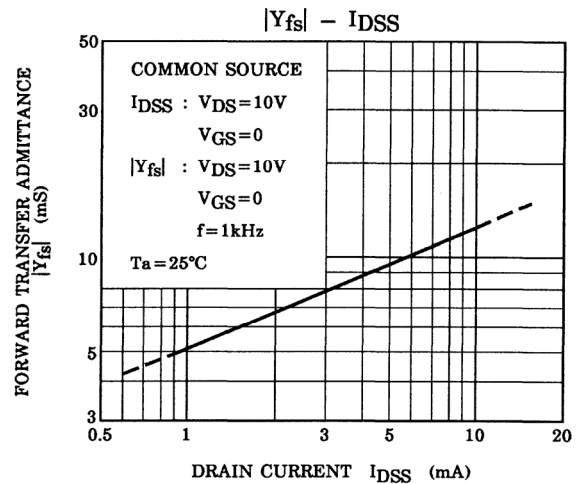
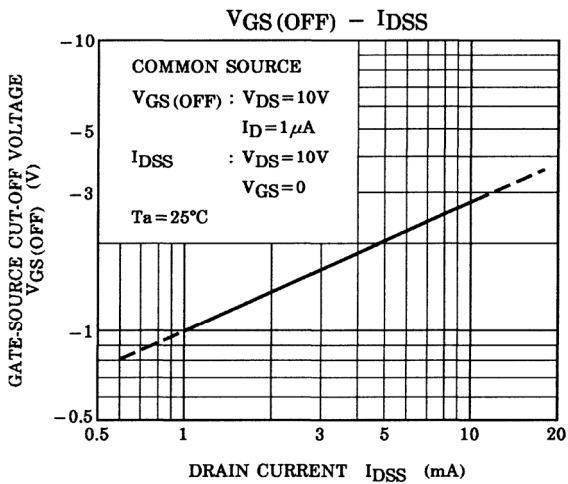
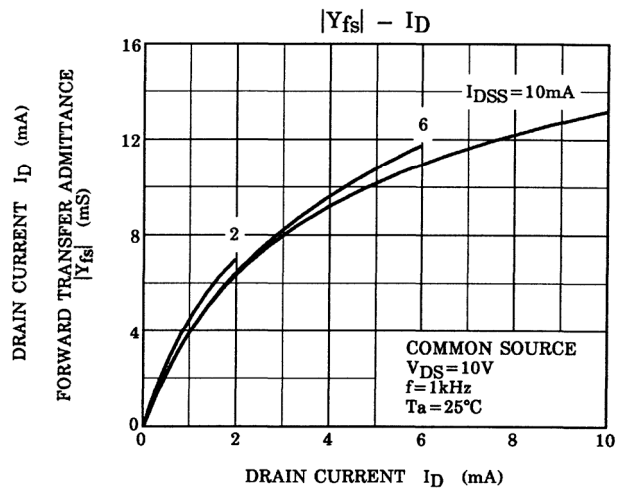
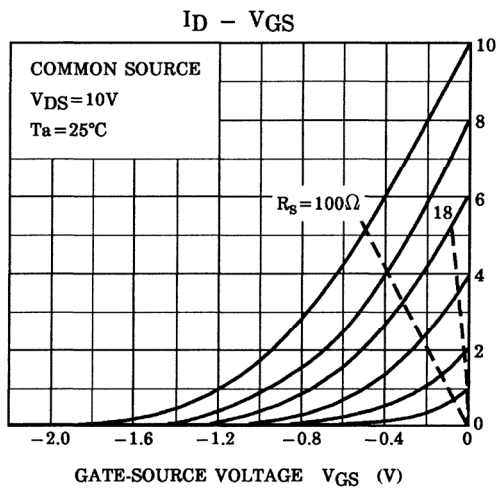
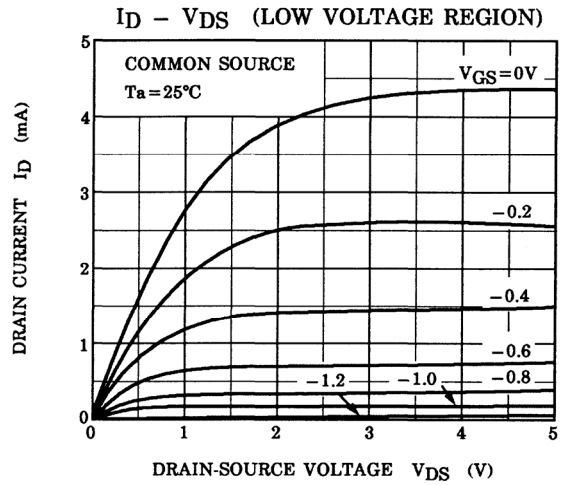
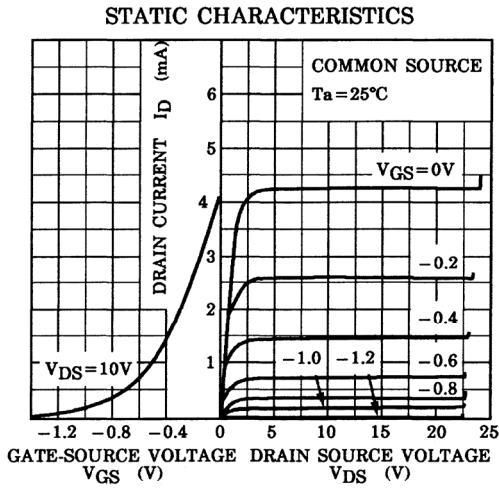
Figure 1 100 MHz GPS, NF Test Circuit

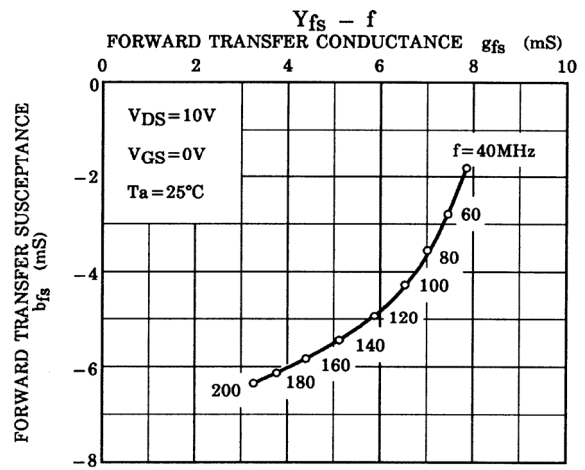
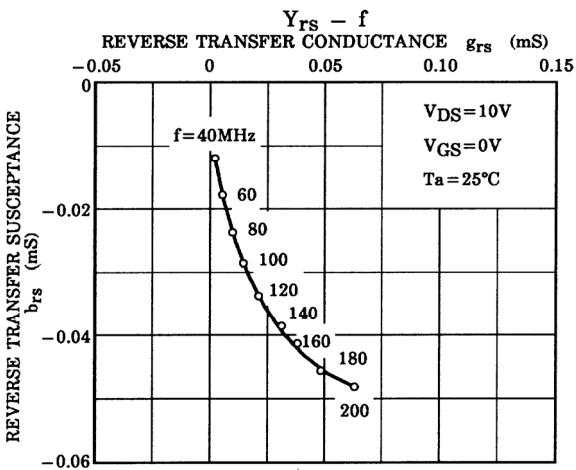
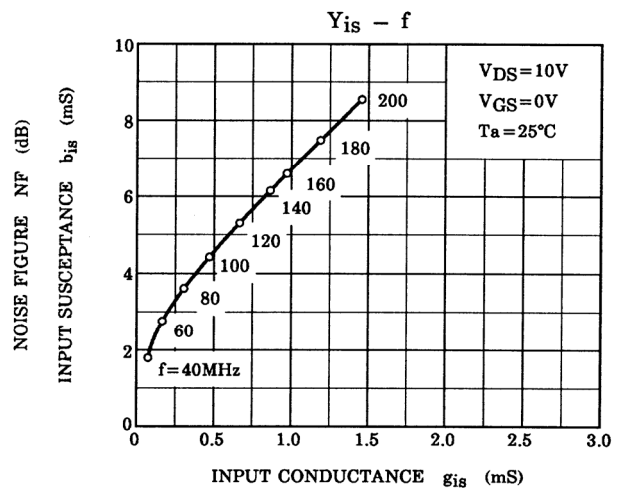
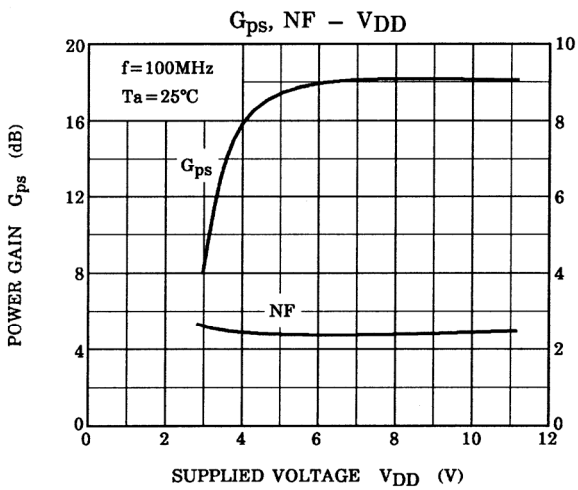
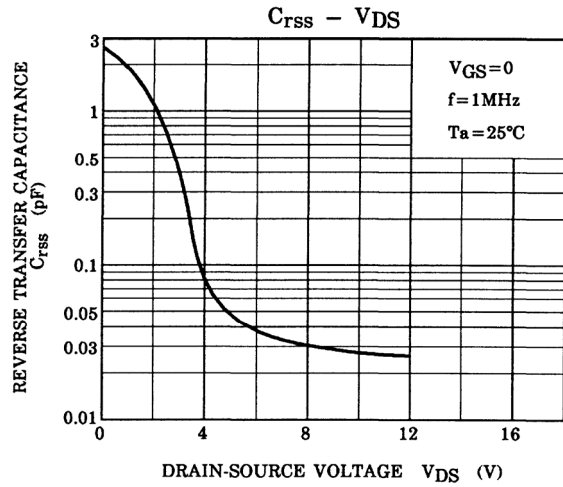
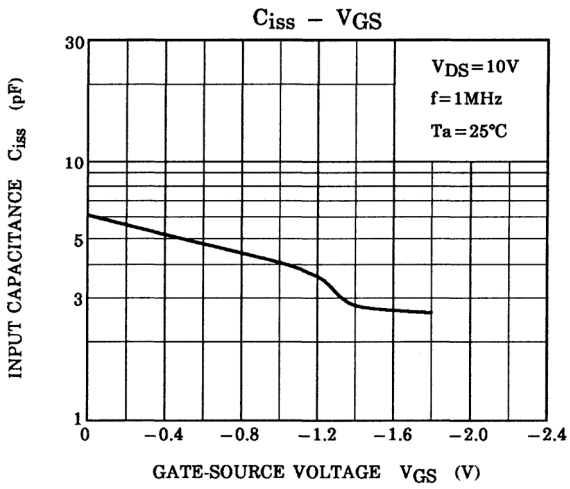
2SK881 is measured at each group by changing R_s .

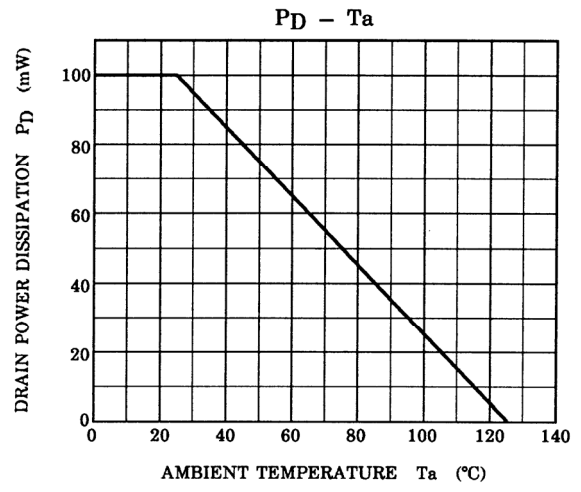
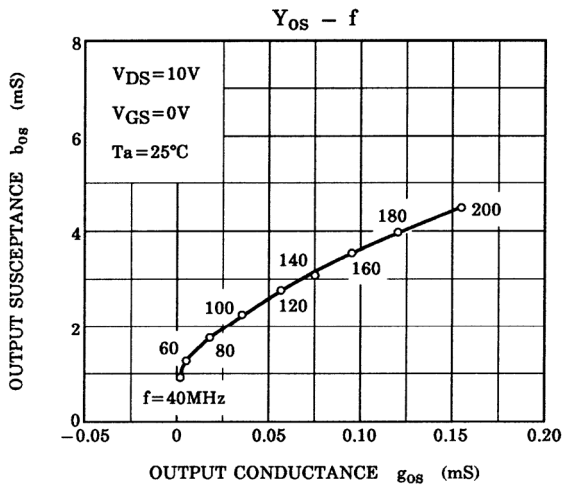
Group	R_s (Ω)
2SK881-O	0
2SK881-Y	$18 \Omega \pm 5\%$
2SK881-GR	$100 \Omega \pm 5\%$

Marking









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20070701-EN GENERAL

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